

Docket #: S03-360

Post-processing Method

A method estimates a nonlinearity profile of a material. The method includes providing a magnitude of a transform of a measured nonlinearity profile measured from the material. The method further includes providing an estimated phase term of the transform of the measured nonlinearity profile. The method further includes multiplying the magnitude and the estimated phase term to generate an estimated transform. The method further includes calculating an inverse transform of the estimated transform. The method further includes calculating a real component of the inverse transform to generate an estimated nonlinearity profile.

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Patents

- Published Application: [2205-00111002](#)
- Published Application: [WO2005054829](#)
- Published Application: [20070282569](#)
- Issued: [7,259,868 \(USA\)](#)

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